Np Barradas

List of Publications by Year
in descending order

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321	5,496	94381	175177
papers	citations	37 h-index	52 g-index

325	325	325	4713
all docs	docs citations	times ranked	citing authors

#	Article	IF	Citations
1	Tantalum-Titanium Oxynitride Thin Films Deposited by DC Reactive Magnetron Co-Sputtering: Mechanical, Optical, and Electrical Characterization. Coatings, 2022, 12, 36.	1.2	6
2	Confronting Vegardâ€™s rule in Ge_{1â^'x}Sn _x epilayers: from fundamentals to the effect of defects. Journal Physics D: Applied Physics, 2022, 55, 295301.	1.3	2
3	TITAN neutron imaging facility performance. Nuclear Instruments and Methods in Physics Research, Section A: Accelerators, Spectrometers, Detectors and Associated Equipment, 2022, 1039, 167078.	0.7	2
4	Microwave transient reflection in annealed SnS thin films. Materials Science in Semiconductor Processing, 2021, 121, 105302.	1.9	5
5	Deposition of Ti-Zr-O-N films by reactive magnetron sputtering of Zr target with Ti ribbons. Surface and Coatings Technology, 2021, 409, 126737.	2.2	3
6	Electrical, optical and photoconductive properties of Sn-doped indium sulfofluoride thin films. Materials Science in Semiconductor Processing, 2021, 121, 105349.	1.9	1
7	In-situ annealing transmission electron microscopy of plasmonic thin films composed of bimetallic Auâ€“Ag nanoparticles dispersed in a TiO2 matrix. Vacuum, 2021, 193, 110511.	1.6	8
8	Fuel retention and erosion-deposition on inner wall cladding tiles in JET-ILW. Physica Scripta, 2021, 96, 124071.	1.2	7
9	Evaluation of tritium retention in plasma facing components during JET tritium operations. Physica Scripta, 2021, 96, 124075.	1.2	14
10	Me-Doped Tiâ€“Me Intermetallic Thin Films Used for Dry Biopotential Electrodes: A Comparative Case Study. Sensors, 2021, 21, 8143.	2.1	5
11	Thin films of Au-Al2O3 for plasmonic sensing. Applied Surface Science, 2020, 500, 144035.	3.1	13
12	Evolution of the mechanical properties of Ti-based intermetallic thin films doped with different metals to be used as biomedical devices. Applied Surface Science, 2020, 505, 144617.	3.1	22
13	Ion beam analysis of fusion plasma-facing materials and components: facilities and research challenges. Nuclear Fusion, 2020, 60, 025001.	1.6	54
14	External beam Total-IBA using DataFurnace. Nuclear Instruments & Methods in Physics Research B, 2020, 481, 47-61.	0.6	9
15	Oxidation behaviour of neutron irradiated Be pebbles. Nuclear Materials and Energy, 2020, 23, 100748.	0.6	3
16	Deposition in the tungsten divertor during the 2011â€“2016 campaigns in JET with ITER-like wall. Physica Scripta, 2020, T171, 014044.	1.2	11
17	W/AlSiTiNx/SiAlTiOyNx/SiAlOx multilayered solar thermal selective absorber coating. Solar Energy, 2020, 207, 192-198.	2.9	18
18	Nanocomposite Au-ZnO thin films: Influence of gold concentration and thermal annealing on the microstructure and plasmonic response. Surface and Coatings Technology, 2020, 385, 125379.	2.2	8

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19	International Atomic Energy Agency inter-comparison of particle induced gamma-ray emission codes for bulk samples. Nuclear Instruments & Methods in Physics Research B, 2020, 468, 37-47.	0.6	11
20	An E-learning tool as living book for knowledge preservation in neutron activation analysis. Journal of Radioanalytical and Nuclear Chemistry, 2020, 325, 737-741.	0.7	2
21	Photoelectrochemical Water Splitting: Thermal Annealing Challenges on Hematite Nanowires. Journal of Physical Chemistry C, 2020, 124, 12897-12911.	1.5	24
22	Metallic filamentary conduction in valence change-based resistive switching devices: the case of TaO_x thin film with x â‰¤ 1. Nanoscale, 2019, 11, 16978-16990.	2.8	16
23	Thin films composed of metal nanoparticles (Au, Ag, Cu) dispersed in AlN: The influence of composition and thermal annealing on the structure and plasmonic response. Thin Solid Films, 2019, 676, 12-25.	0.8	20
24	The effect of increasing Si content in the absorber layers (CrAlSiNx/CrAlSiOyNx) of solar selective absorbers upon their selectivity and thermal stability. Applied Surface Science, 2019, 481, 1096-1102.	3.1	7
25	Optical and photoconductive properties of indium sulfide fluoride thin films. Thin Solid Films, 2019, 671, 49-52.	0.8	5
26	Influence of Al/Si atomic ratio on optical and electrical properties of magnetron sputtered Al1-xSixOy coatings. Thin Solid Films, 2019, 669, 475-481.	0.8	4
27	Deposition temperature influence on the wear behaviour of carbon-based coatings deposited on hardened steel. Applied Surface Science, 2019, 475, 762-773.	3.1	9
28	Compositional analysis by RBS, XPS and EDX of ZnO:Al,Bi and ZnO:Ga,Bi thin films deposited by d.c. magnetron sputtering. Vacuum, 2019, 161, 268-275.	1.6	26
29	CrAlSiN barrier layer to improve the thermal stability of W/CrAlSiNx/CrAlSiOyNx/SiAlOx solar thermal absorber. Solar Energy Materials and Solar Cells, 2019, 191, 235-242.	3.0	17
30	A study of solar thermal absorber stack based on CrAlSiNx/CrAlSiNxOy structure by ion beams. Nuclear Instruments & Methods in Physics Research B, 2019, 450, 195-199.	0.6	5
31	Thin films of Agâ€“Au nanoparticles dispersed in TiO₂: influence of composition and microstructure on the LSPR and SERS responses. Journal Physics D: Applied Physics, 2018, 51, 205102.	1.3	30
32	Up-conversion emission of aluminosilicate and titania films doped with Er3+/Yb3+ by ion implantation and sol-gel solution doping. Surface and Coatings Technology, 2018, 355, 162-168.	2.2	14
33	A design of selective solar absorber for high temperature applications. Solar Energy, 2018, 172, 177-183.	2.9	38
34	Optimization of nanocomposite Au/TiO 2 thin films towards LSPR optical-sensing. Applied Surface Science, 2018, 438, 74-83.	3.1	54
35	Zr-O-N coatings for decorative purposes: Study of the system stability by exploration of the deposition parameter space. Surface and Coatings Technology, 2018, 343, 30-37.	2.2	23
36	In-situ XRD vs ex-situ vacuum annealing of tantalum oxynitride thin films: Assessments on the structural evolution. Applied Surface Science, 2018, 438, 14-19.	3.1	1

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37	Thin films composed of Au nanoparticles embedded in AlN: Influence of metal concentration and thermal annealing on the LSPR band. Vacuum, 2018, 157, 414-421.	1.6	24
38	Assessment of erosion, deposition and fuel retention in the JET-ILW divertor from ion beam analysis data. Nuclear Materials and Energy, 2017, 12, 559-563.	0.6	28
39	Optical and structural analysis of solar selective absorbing coatings based on AlSiOx:W cermets. Solar Energy, 2017, 150, 335-344.	2.9	40
40	Overview of the JET ITER-like wall divertor. Nuclear Materials and Energy, 2017, 12, 499-505.	0.6	46
41	Characterization of magnetron sputtered sub-stoichiometric CrAlSiN x and CrAlSiO y N x coatings. Surface and Coatings Technology, 2017, 328, 134-141.	2.2	18
42	Overview of fuel inventory in JET with the ITER-like wall. Nuclear Fusion, 2017, 57, 086045.	1.6	47
43	Corrosion Behavior of Titanium Oxynitrided by Diffusion and Magnetron Sputtering Methods in Physiological Solution. Materials Performance and Characterization, 2017, 6, 594-606.	0.2	0
44	Ag:TiNâ€€coated Polyurethane for Dry Biopotential Electrodes: From Polymer Plasma Interface Activation to the First EEG Measurements. Plasma Processes and Polymers, 2016, 13, 341-354.	1.6	27
45	Composition measurement of epitaxial Sc_xGa_{1â^'x}N films. Semiconductor Science and Technology, 2016, 31, 064002.	1.0	3
46	Electrical insulation properties of RF-sputtered LiPON layers towards electrochemical stability of lithium batteries. Journal Physics D: Applied Physics, 2016, 49, 485301.	1.3	7
47	Determination of 9Be(p,p0)9Be, 9Be(p,d0)8Be and 9Be(p,Î±0)6Li cross sections at 150Â° in the energy range 0.5â€“2.35 MeV. Nuclear Instruments & Methods in Physics Research B, 2016, 371, 50-53.	0.6	9
48	The role and application of ion beam analysis for studies of plasma-facing components in controlled fusion devices. Nuclear Instruments & Methods in Physics Research B, 2016, 371, 4-11.	0.6	18
49	Functional behaviour of TiO₂ films doped with noble metals. Surface Engineering, 2016, 32, 554-561.	1.1	14
50	Electrochemical characterization of nanostructured Ag:TiN thin films produced by glancing angle deposition on polyurethane substrates for bio-electrode applications. Journal of Electroanalytical Chemistry, 2016, 768, 110-120.	1.9	12
51	Long-term fuel retention in JET ITER-like wall. Physica Scripta, 2016, T167, 014075.	1.2	52
52	Analytical simulation of RBS spectra of nanowire samples. Nuclear Instruments & Methods in Physics Research B, 2016, 371, 116-120.	0.6	9
53	The influence of the beam charge state on the analytical calculation of RBS and ERDA spectra. Nuclear Instruments & Methods in Physics Research B, 2016, 371, 121-124.	0.6	2
54	Quantitative Chemical Mapping of InGaN Quantum Wells from Calibrated High-Angle Annular Dark Field Micrographs. Microscopy and Microanalysis, 2015, 21, 994-1005.	0.2	3

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55	The effect of metalâ€rich growth conditions on the microstructure of Sc_xGa_{1â^'x}N films grown using molecular beam epitaxy. Physica Status Solidi (A) Applications and Materials Science, 2015, 212, 2837-2842.	0.8	14
56	Tribological characterization of TiO 2 /Au decorative thin films obtained by PVD magnetron sputtering technology. Wear, 2015, 330-331, 419-428.	1.5	13
57	Fuel retention in JET ITER-Like Wall from post-mortem analysis. Journal of Nuclear Materials, 2015, 463, 961-965.	1.3	50
58	Multifunctional Tiâ€“Me (Me=Al, Cu) thin film systems for biomedical sensing devices. Vacuum, 2015, 122, 353-359.	1.6	20
59	Laser-induced diffusion decomposition in Feâ€“V thin-film alloys. Applied Surface Science, 2015, 336, 380-384.	3.1	2
60	Solar selective absorbers based on Al2O3:W cermets and AlSiN/AlSiON layers. Solar Energy Materials and Solar Cells, 2015, 137, 93-100.	3.0	68
61	Determination of the 9Be(3He,pi)11B (i=0,1,2,3) cross section at 135Â° in the energy range 1â€“2.5MeV. Nuclear Instruments & Methods in Physics Research B, 2015, 346, 21-25.	0.6	24
62	Electrochemical and structural characterization of nanocomposite Agy:TiNx thin films for dry bioelectrodes: the effect of the N/Ti ratio and Ag content. Electrochimica Acta, 2015, 153, 602-611.	2.6	9
63	Study of the electrical behavior of nanostructured Tiâ€“Ag thin films, prepared by Glancing Angle Deposition. Materials Letters, 2015, 157, 188-192.	1.3	13
64	Biological behaviour of thin films consisting of Au nanoparticles dispersed in a TiO2 dielectric matrix. Vacuum, 2015, 122, 360-368.	1.6	20
65	Modifying polyester surfaces with incompatible polymer additives. Reactive and Functional Polymers, 2015, 89, 40-48.	2.0	12
66	Ag y :TiN x thin films for dry biopotential electrodes: the effect of composition and structural changes on the electrical and mechanical behaviours. Applied Physics A: Materials Science and Processing, 2015, 119, 169-178.	1.1	2
67	Structure dependent resistivity and dielectric characteristics of tantalum oxynitride thin films produced by magnetron sputtering. Applied Surface Science, 2015, 354, 298-305.	3.1	14
68	Determination of molecular stopping cross section of 12C, 16O, 28Si, 35Cl, 58Ni, 79Br, and 127I in silicon nitride. Nuclear Instruments & Methods in Physics Research B, 2015, 360, 90-96.	0.6	4
69	Composition and structure variation for magnetron sputtered tantalum oxynitride thin films, as function of deposition parameters. Applied Surface Science, 2015, 358, 508-517.	3.1	7
70	Global erosion and deposition patterns in JET with the ITER-like wall. Journal of Nuclear Materials, 2015, 463, 157-161.	1.3	48
71	Ion beam analysis of Cu(In,Ga)Se 2 thin film solar cells. Applied Surface Science, 2015, 356, 631-638.	3.1	15
72	Optical properties of zirconium oxynitride films: The effect of composition, electronic and crystalline structures. Applied Surface Science, 2015, 358, 660-669.	3.1	19

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73	Optical performance of thin films produced by the pulsed laser deposition of SiAlON and Er targets. Applied Surface Science, 2015, 336, 274-277.	3.1	6
74	Evolution of the functional properties of titaniumâ€“silver thin films for biomedical applications: Influence of in-vacuum annealing. Surface and Coatings Technology, 2015, 261, 262-271.	2.2	19
75	Fixed and free line ratio DT2 PIXE fitting and simulation package. Nuclear Instruments & Methods in Physics Research B, 2014, 318, 65-69.	0.6	8
76	New experimental molecular stopping cross section data of Al2O3, for heavy ions. Nuclear Instruments & Methods in Physics Research B, 2014, 332, 341-345.	0.6	7
77	Stopping power of 1H and 4He in lithium niobate. Nuclear Instruments & Methods in Physics Research B, 2014, 332, 330-333.	0.6	3
78	Optimisation of surface treatments of TiO2:Nb transparent conductive coatings by a post-hot-wire annealing in a reducing H2 atmosphere. Thin Solid Films, 2014, 550, 404-412.	0.8	20
79	Electrochemical behaviour of nanocomposite Agx:TiN thin films for dry biopotential electrodes. Electrochimica Acta, 2014, 125, 48-57.	2.6	30
80	Surface analysis of tiles and samples exposed to the first JET campaigns with the ITER-like wall. Physica Scripta, 2014, T159, 014012.	1.2	35
81	Stopping power of C, O and Cl in tantalum oxide. Nuclear Instruments & Methods in Physics Research B, 2014, 332, 152-155.	0.6	5
82	In-depth elemental characterization of Cu(In,Ga)Se2 thin film solar cells by means of RBS and PIXE techniques. Nuclear Instruments & Methods in Physics Research B, 2014, 331, 93-95.	0.6	7
83	IBA study of SiGe/SiO2 nanostructured multilayers. Nuclear Instruments & Methods in Physics Research B, 2014, 331, 89-92.	0.6	3
84	An open source package for the IBA data format IDF. Nuclear Instruments & Methods in Physics Research B, 2014, 332, 148-151.	0.6	2
85	On the formation of an interface amorphous layer in nanostructured ferroelectric Ba0.8Sr0.2TiO3 thin films integrated on Ptâ€“Si and its effect on the electrical properties. Applied Surface Science, 2013, 278, 136-141.	3.1	11
86	Influence of RF-sputtering power on formation of vertically stacked Si_{1â^'x}Ge_xnanocrystals between ultra-thin amorphous Al₂O₃layers: structural and photoluminescence properties. Journal Physics D: Applied Physics, 2013, 46, 385301.	1.3	1
87	TiAgx thin films for lower limb prosthesis pressure sensors: Effect of composition and structural changes on the electrical and thermal response of the films. Applied Surface Science, 2013, 285, 10-18.	3.1	34
88	Nanocomposite Ag:TiN thin films for dry biopotential electrodes. Applied Surface Science, 2013, 285, 40-48.	3.1	38
89	Status of the MARE Experiment. IEEE Transactions on Applied Superconductivity, 2013, 23, 2101204-2101204.	1.1	3
90	Influence of stoichiometry and structure on the optical properties of AlN_xO_y films. Journal Physics D: Applied Physics, 2013, 46, 015305.	1.3	24

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91	On the growth kinetics of Ni(Pt) silicide thin films. Journal of Applied Physics, 2013, 113, .	1.1	17
92	Properties of tantalum oxynitride thin films produced by magnetron sputtering: The influence of processing parameters. Vacuum, 2013, 98, 63-69.	1.6	33
93	Measurement and evaluation of the 13C(p,p)13C cross section in the energy range 0.8â€“2.4MeV. Nuclear Instruments & Methods in Physics Research B, 2013, 316, 81-87.	0.6	5
94	Development of tantalum oxynitride thin films produced by PVD: Study of structural stability. Applied Surface Science, 2013, 285, 19-26.	3.1	13
95	Local deposition of 13C tracer in the JET MKII-HD divertor. Journal of Nuclear Materials, 2013, 438, S762-S765.	1.3	1
96	Influence of composition, bonding characteristics and microstructure on the electrochemical and optical stability of AlOxNy thin films. Electrochimica Acta, 2013, 106, 23-34.	2.6	11
97	TiO₂ coatings with Au nanoparticles analysed by photothermal IR radiometry. Journal Physics D: Applied Physics, 2012, 45, 105301.	1.3	17
98	Tuning the properties of Ge-quantum dots superlattices in amorphous silica matrix through deposition conditions. Journal of Applied Physics, 2012, 111, 074316.	1.1	4
99	In situ study of the growth properties of Ni-rare earth silicides for interlayer and alloy systems on Si(100). Journal of Applied Physics, 2012, 111, 043511.	1.1	6
100	Influence of annealing conditions on the formation of regular lattices of voids and Ge quantum dots in an amorphous alumina matrix. Nanotechnology, 2012, 23, 405605.	1.3	8
101	Electrical properties of AlNxOy thin films prepared by reactive magnetron sputtering. Thin Solid Films, 2012, 520, 6709-6717.	0.8	24
102	The influence of annealing treatments on the properties of Ag:TiO2 nanocomposite films prepared by magnetron sputtering. Applied Surface Science, 2012, 258, 4028-4034.	3.1	49
103	TiNx coated polycarbonate for bio-electrode applications. Corrosion Science, 2012, 56, 49-57.	3.0	37
104	Accurate Determination of Quantity of Material in Thin Films by Rutherford Backscattering Spectrometry. Analytical Chemistry, 2012, 84, 6061-6069.	3.2	96
105	Structural and electrical studies of ultrathin layers with Si0.7Ge0.3 nanocrystals confined in a SiGe/SiO2 superlattice. Journal of Applied Physics, 2012, 111, 104323.	1.1	10
106	Structural and optical studies of Au doped titanium oxide films. Nuclear Instruments & Methods in Physics Research B, 2012, 272, 61-65.	0.6	16
107	Stopping power of He, C and O in TiO2. Nuclear Instruments & Methods in Physics Research B, 2012, 273, 22-25.	0.6	8
108	Stopping power of He, C and O in GaN. Nuclear Instruments & Methods in Physics Research B, 2012, 273, 26-29.	0.6	3

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109	Stopping power of C in Si. Nuclear Instruments & Methods in Physics Research B, 2012, 273, 30-32.	0.6	5
110	High precision determination of the InN content of Al1â^'xInxN thin films by Rutherford backscattering spectrometry. Nuclear Instruments & Methods in Physics Research B, 2012, 273, 105-108.	0.6	8
111	Incorporation of N in TiO2 films grown by DC-reactive magnetron sputtering. Nuclear Instruments & Methods in Physics Research B, 2012, 273, 109-112.	0.6	13
112	Characterization of nanostructured HfO2 films using RBS and PAC. Nuclear Instruments & Methods in Physics Research B, 2012, 273, 195-198.	0.6	1
113	The width of an RBS spectrum revisited: Influence of multiple scattering. Nuclear Instruments & Methods in Physics Research B, 2012, 270, 44-46.	0.6	2
114	Analysis of multifunctional titanium oxycarbide films as a function of oxygen addition. Surface and Coatings Technology, 2012, 206, 2525-2534.	2.2	27
115	Tuning of the surface plasmon resonance in TiO2/Au thin films grown by magnetron sputtering: The effect of thermal annealing. Journal of Applied Physics, 2011, 109, .	1.1	74
116	Surface composition and morphology changes of JET tiles under plasma interactions. Fusion Engineering and Design, 2011, 86, 2557-2560.	1.0	6
117	Deposition of13C tracer in the JET MkII-HD divertor. Physica Scripta, 2011, T145, 014004.	1.2	15
118	Development of a reference database for Ion Beam Analysis and future perspectives. Nuclear Instruments & Methods in Physics Research B, 2011, 269, 2972-2978.	0.6	37
119	Characterization of mercury gilding art objects by external proton beam. Nuclear Instruments & Methods in Physics Research B, 2011, 269, 3049-3053.	0.6	17
120	Materials research under ITER-like divertor conditions at FOM Rijnhuizen. Journal of Nuclear Materials, 2011, 417, 457-462.	1.3	1
121	Low-temperature fabrication of layered self-organized Ge clusters by RF-sputtering. Nanoscale Research Letters, 2011, 6, 341.	3.1	18
122	PIXE analysis of multilayer targets. X-Ray Spectrometry, 2011, 40, 153-156.	0.9	6
123	Preparation and characterization of CrNxOy thin films: The effect of composition and structural features on the electrical behavior. Applied Surface Science, 2011, 257, 9120-9124.	3.1	19
124	Influence of the deposition parameters on the growth of SiGe nanocrystals embedded in Al2O3 matrix. Microelectronic Engineering, 2011, 88, 509-513.	1.1	8
125	Optimization Of A Mass Spectrometry Process. , 2011, , .		0
126	A Double Scattering Analytical Model For Elastic Recoil Detection Analysis. , 2011, , .		1

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127	IBIXFIT: A Tool For The Analysis Of Microcalorimeter PIXE Spectra. , 2011, , .		3
128	Integration Of SIMS Into A General Purpose IBA Data Analysis Code. AIP Conference Proceedings, 2011, , .	0.3	4
129	Hydrogen In Group-III Nitrides: An Ion Beam Analysis Study. , 2011, , .		1
130	Stopping Power Of He, C And O In InN. , 2011, , .		2
131	Measurements and Evaluation of Differential Cross-sections for In Beam Analysis. Journal of the Korean Physical Society, 2011, 59, 2010-2013.	0.3	1
132	N-Doped Photocatalytic Titania Thin Films on Active Polymer Substrates. Journal of Nanoscience and Nanotechnology, 2010, 10, 1072-1077.	0.9	11
133	Influence of temperature and plasma composition on deuterium retention in refractory metals. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 2124-2128.	0.6	2
134	Multilayers of Ge nanocrystals embedded in Al2O3 matrix: Structural and electrical studies. Microelectronic Engineering, 2010, 87, 2508-2512.	1.1	8
135	Carbon film growth and hydrogenic retention of tungsten exposed to carbon-seeded high density deuterium plasmas. Journal of Nuclear Materials, 2010, 396, 176-180.	1.3	2
136	Stopping power of 11B in Si and TiO2 measured with a bulk sample method and Bayesian inference data analysis. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 1768-1771.	0.6	10
137	Thin film depth profiling using simultaneous particle backscattering and nuclear resonance profiling. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 1829-1832.	0.6	18
138	A new ion beam analysis data format. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 1824-1828.	0.6	3
139	High Resolution and Differential PIXE combined with RBS, EBS and AFM analysis of magnesium titanate (MgTiO3) multilayer structures. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 1980-1985.	0.6	20
140	Erosion and re-deposition processes in JET tiles studied with ion beams. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 1991-1996.	0.6	15
141	CdTe detector use for PIXE characterization of TbCoFe thin films. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 2010-2014.	0.6	10
142	Artificial neural networks for instantaneous analysis of real-time Rutherford backscattering spectra. Nuclear Instruments & Methods in Physics Research B, 2010, 268, 1676-1681.	0.6	24
143	Structural study of Si1â^'xGex nanocrystals embedded in SiO2 films. Thin Solid Films, 2010, 518, 2569-2572.	0.8	9
144	Validation of the Monte Carlo model supporting core conversion of the Portuguese Research Reactor (RPI) for neutron fluence rate determinations. Annals of Nuclear Energy, 2010, 37, 1139-1145.	0.9	36

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145	Functional and optical properties of Au:TiO2 nanocomposite films: The influence of thermal annealing. Applied Surface Science, 2010, 256, 6536-6542.	3.1	43
146	Al1â˜'xInxN/GaN bilayers: Structure, morphology, and optical properties. Physica Status Solidi (B): Basic Research, 2010, 247, 1740-1746.	0.7	10
147	Total reflectance and Raman studies in Al_yIn_xGa_{1â€xâ€y}N epitaxial layers. Physica Status Solidi C: Current Topics in Solid State Physics, 2010, 7, 56-59.	0.8	0
148	Growth and characterization of Mnâ€doped ZnO/TiO₂ multilayer nanostructures grown by pulsed laser deposition. Physica Status Solidi C: Current Topics in Solid State Physics, 2010, 7, 2724-2726.	0.8	0
149	Effect of annealing on AlN/GaN quantum dot heterostructures: advanced ion beam characterization and Xâ€ray study of lowâ€dimensional structures. Surface and Interface Analysis, 2010, 42, 1552-1555.	0.8	6
150	Electrical and Raman Scattering Studies of ZnO:P and ZnO:Sb Thin Films. Journal of Nanoscience and Nanotechnology, 2010, 10, 2620-2623.	0.9	8
151	Hydrogenic retention of high-Z refractory metals exposed to ITER divertor-relevant plasma conditions. Nuclear Fusion, 2010, 50, 055004.	1.6	17
152	Hydrogen in InN: A ubiquitous phenomenon in molecular beam epitaxy grown material. Applied Physics Letters, 2010, 96, .	1.5	36
153	Mn-doped ZnO nanocrystals embedded in Al₂O₃: structural and electrical properties. Nanotechnology, 2010, 21, 505705.	1.3	11
154	Stopping Power of Different Ions in Si Measured with a Bulk Sample Method and Bayesian Inference Data Analysis. , 2009, , .		9
155	Enhancement in the photocatalytic nature of nitrogen-doped PVD-grown titanium dioxide thin films. Journal of Applied Physics, 2009, 106, .	1.1	37
156	Structural and optical characterization of Eu-implanted GaN. Journal Physics D: Applied Physics, 2009, 42, 165103.	1.3	48
157	Intrinsic <I>p</I> Type ZnO Films Deposited by rf Magnetron Sputtering. Journal of Nanoscience and Nanotechnology, 2009, 9, 813-816.	0.9	7
158	Hydrogenic retention in tungsten exposed to ITER divertor relevant plasma flux densities. Journal of Nuclear Materials, 2009, 390-391, 610-613.	1.3	14
159	Role of impurities and dislocations for the unintentional n-type conductivity in InN. Physica B: Condensed Matter, 2009, 404, 4476-4481.	1.3	15
160	Structural evolution of Tiâ€“Alâ€“Siâ€“N nanocomposite coatings. Vacuum, 2009, 83, 1206-1212.	1.6	36
161	Structural and optical properties of nitrogen doped ZnO films. Vacuum, 2009, 83, 1274-1278.	1.6	11
162	Annealing Ni nanocrystalline on WCâ€“Co. Journal of Alloys and Compounds, 2009, 482, 131-136.	2.8	2

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163	ZrO_xN_ydecorative thin films prepared by the reactive gas pulsing process. Journal Physics D: Applied Physics, 2009, 42, 195501.	1.3	24
164	Ion Beam Analysis of Iridium-Based TES for Microcalorimeter Detectors. , 2009, , .		0
165	Advanced physics and algorithms in the IBA DataFurnace. Nuclear Instruments & Methods in Physics Research B, 2008, 266, 1875-1879.	0.6	145
166	RBS analysis of InGaN/GaN quantum wells for hybrid structures with efficient FÃ¶rster coupling. Nuclear Instruments & Methods in Physics Research B, 2008, 266, 1402-1406.	0.6	2
167	Determination of non-Rutherford cross-sections from simple RBS spectra using Bayesian inference data analysis. Nuclear Instruments & Methods in Physics Research B, 2008, 266, 1180-1184.	0.6	12
168	DT2, a PIXE spectra simulation and fitting package. X-Ray Spectrometry, 2008, 37, 100-102.	0.9	16
169	Growth of GaInSb concentrated alloys under alternating magnetic field. Journal of Crystal Growth, 2008, 310, 1424-1432.	0.7	8
170	Memory effect on CdSe nanocrystals embedded in SiO2 matrix. Solid State Communications, 2008, 148, 105-108.	0.9	11
171	Summary of â€œIAEA intercomparison of IBA softwareâ€• Nuclear Instruments & Methods in Physics Research B, 2008, 266, 1338-1342.	0.6	69
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